

This material and the information herein is the property of Fuji Electric Co., Ltd. They shall be neither reproduced, copied, lent, or disclosed in any way whatsoever for the use of any third party nor used for the manufacturing purposes without the express written consent of Fuji Electric Co., Ltd.

SPECIFICATION

(TENTATIVE)

Device Name : Power MOSFET
Type Name : 2SK3272-01L,S,SJ
Spec. No. : MS5F4394

Fuji Electric Co., Ltd.
Matsumoto Factory

	DATE	NAME	APPROVED	Fuji Electric Co., Ltd.	
DRAWN	Aug. - 24 - '98	T. Shimatsu		DWG. NO.	MS5F4394
CHECKED	Aug. - 24 - '98	T. Yamada			
		T. Goto			1/15

H04-004-05

- 1.Scope** This specifies Fuji Power MOSFET 2SK3272-01L,S,SJ
- 2.Construction** N-Channel enhancement mode power MOSFET
- 3.Applications** for Switching
- 4.Outview** T-pack L-Type Outview See to 5/15 page
S-Type Outview See to 6/15 page
SJ-Type Outview See to 7/15 page

5.Absolute Maximum Ratings at $T_c=25^{\circ}\text{C}$ (unless otherwise specified)

Description	Symbol	Characteristics	Unit	Remarks
Drain-Source Voltage	V_{DS}	60	V	
	V_{DSX}	40	V	$V_{GS}=-20\text{V}$
Continuous Drain Current	I_D	± 80	A	
Pulsed Drain Current	I_{DP}	± 320	A	
Gate-Source Voltage	V_{GS}	+30/-20	V	
Maximum Avalanche Energy	E_{AV}	613	mJ	*1
Maximum Power Dissipation	P_D	135	W	
Operating and Storage Temperature range	T_{ch}	150	$^{\circ}\text{C}$	
	T_{slg}	-55 to +150	$^{\circ}\text{C}$	

*1 $L=0.13\text{mH}$, $V_{CC}=24\text{V}$

6.Electrical Characteristics at $T_c=25^{\circ}\text{C}$ (unless otherwise specified)

Static Ratings

Description	Symbol	Conditions	min.	typ.	max.	Unit
Drain-Source Breakdown Voltage	BV_{DSS}	$I_D=1\text{mA}$ $V_{GS}=0\text{V}$	60	-	-	V
	BV_{DSX}	$I_D=1\text{mA}$ $V_{GS}=-20\text{V}$	40	-	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$I_D=10\text{mA}$ $V_{DS}=V_{GS}$	2.5	3.0	3.5	V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=60\text{V}$ $T_{ch}=25^{\circ}\text{C}$	-	1.0	100	μA
		$V_{GS}=0\text{V}$ $T_{ch}=125^{\circ}\text{C}$	-	10	500.0	μA
Gate-Source Leakage Current	I_{GSS}	$V_{GS}=+30\text{V}, -20\text{V}$ $V_{DS}=0\text{V}$	-	10	100	nA
Drain-Source On-State Resistance	$R_{DS(on)}$	$I_D=40\text{A}$ $V_{GS}=10\text{V}$	-	5.0	6.5	m Ω

Dynamic Ratings

Description	Symbol	Conditions	min.	typ.	max.	Unit
Forward Transconductance	g_{fs}	$I_D=40A$ $V_{DS}=10V$	25	50	-	S
Input Capacitance	C_{iss}	$V_{DS}=25V$ $V_{GS}=0V$ $f=1MHz$	-	9000	-	pF
Output Capacitance	C_{oss}		-	1250	-	
Reverse Transfer Capacitance	C_{rss}		-	700	-	
Turn-On Time	$t_d(on)$	$V_{cc}=30V$	-	50	-	ns
	t_r	$V_{GS}=10V$	-	200	-	
Turn-Off Time	$t_d(off)$	$I_D=80A$	-	150	-	
	t_f	$R_G=10\Omega$	-	135	-	
Total Gate Charge	Q_g	$V_{cc}=30V$	-	145	-	ns
Gate - Source Charge	Q_{gs}	$I_D=80A$	-	60	-	
Gate - Drain Charge	Q_{gd}	$V_{GS}=10V$	-	40	-	

Reverse Diode

Description	Symbol	Conditions	min.	typ.	max.	Unit
Avalanche Capability	I_{AV}	$L=100\mu H$ $T_{ch}=25^\circ C$ See Fig.1 and Fig.2	80	-	-	A
Diode Forward On-Voltage	V_{SD}	$I_F=80A$ $V_{GS}=0V$ $T_{ch}=25^\circ C$	-	1.0	1.5	V
Reverse Recovery Time	t_{rr}	$I_F=50A$ $V_{GS}=0V$	-	85	-	ns
Reverse Recovery Charge	Q_{rr}	$-di/dt=100A/\mu s$ $T_{ch}=25^\circ C$	-	0.25	-	μC

7.Thermal Resistance

Description	Symbol	min.	typ.	max.	Unit
Channel to Case	$R_{th(ch-c)}$	-	-	0.926	$^\circ C/W$
Channel to Ambient	$R_{th(ch-a)}$	-	-	75.0	$^\circ C/W$

Fig.1 Test circuit

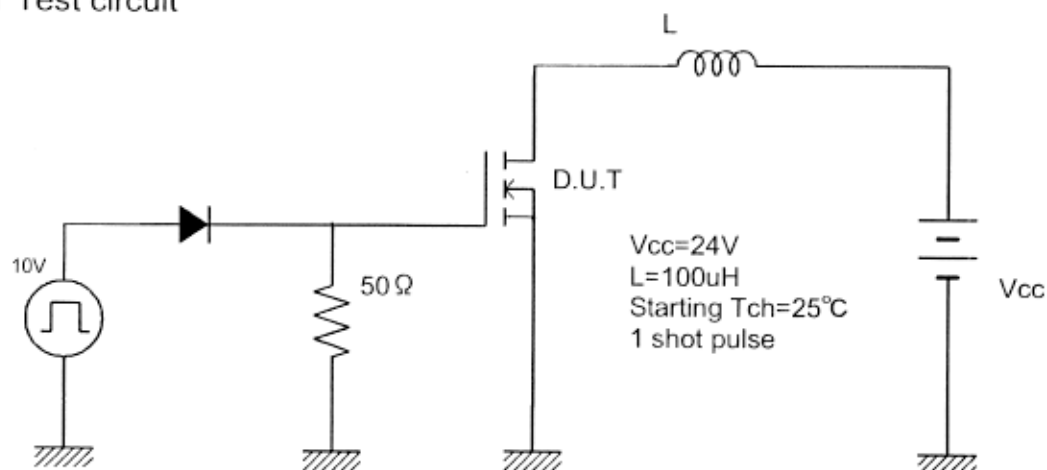
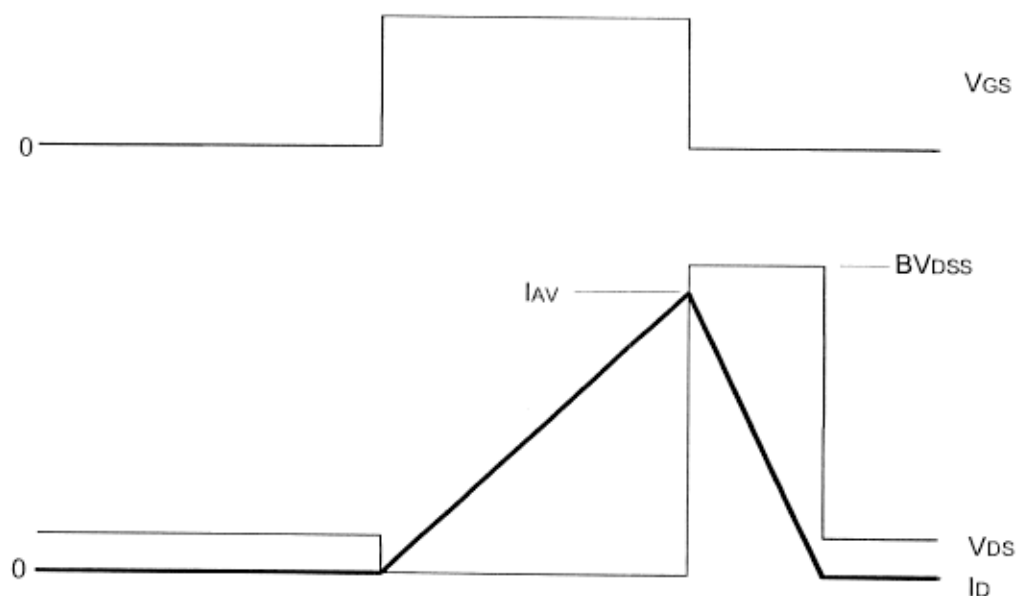
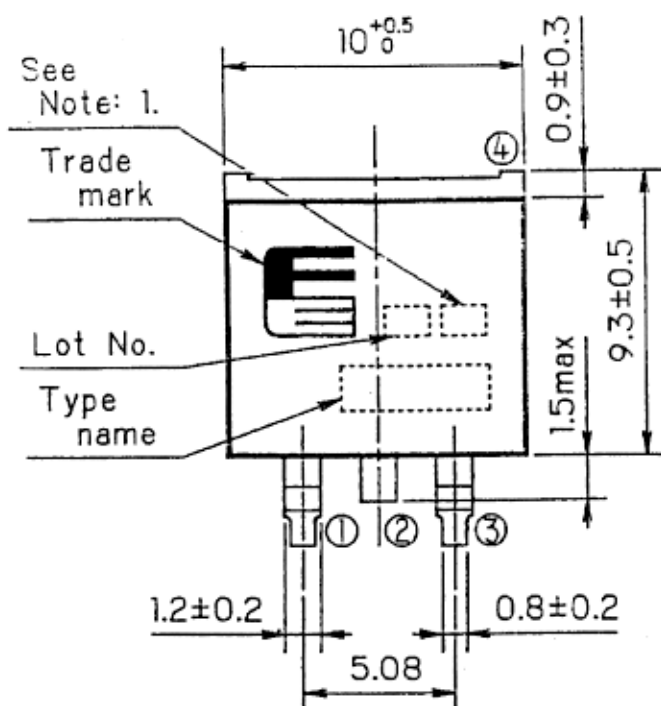
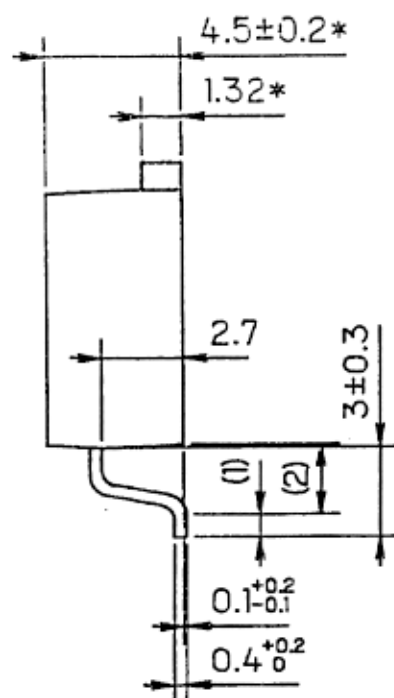


Fig.2 Operating waveforms



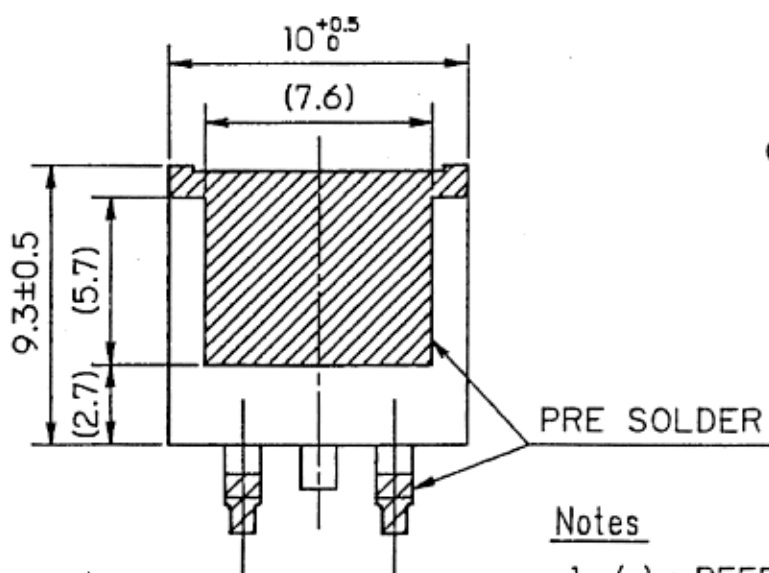


BOTTOM VIEW



CONNECTION

- ① GATE
- ④ ② DRAIN
- ③ SOURCE



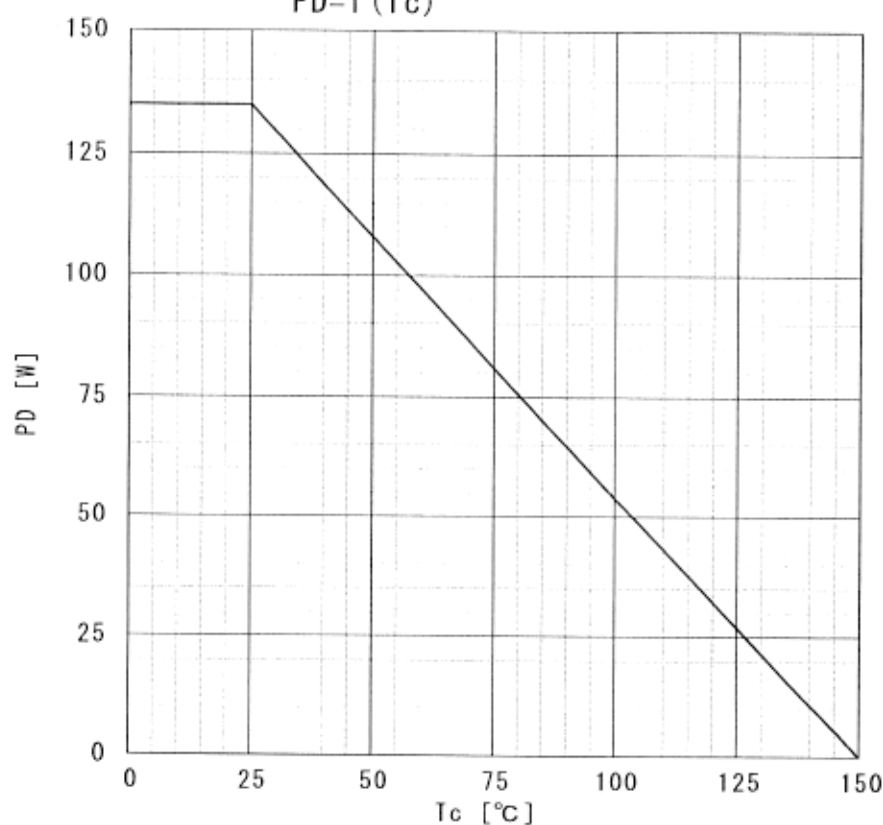
Notes

Note: 1. Guaranteed mark of avalanche ruggedness.

- 1. () : REFERENCE DIMENSIONS.
- 2. * : DO NOT INCLUDE SOLDER.

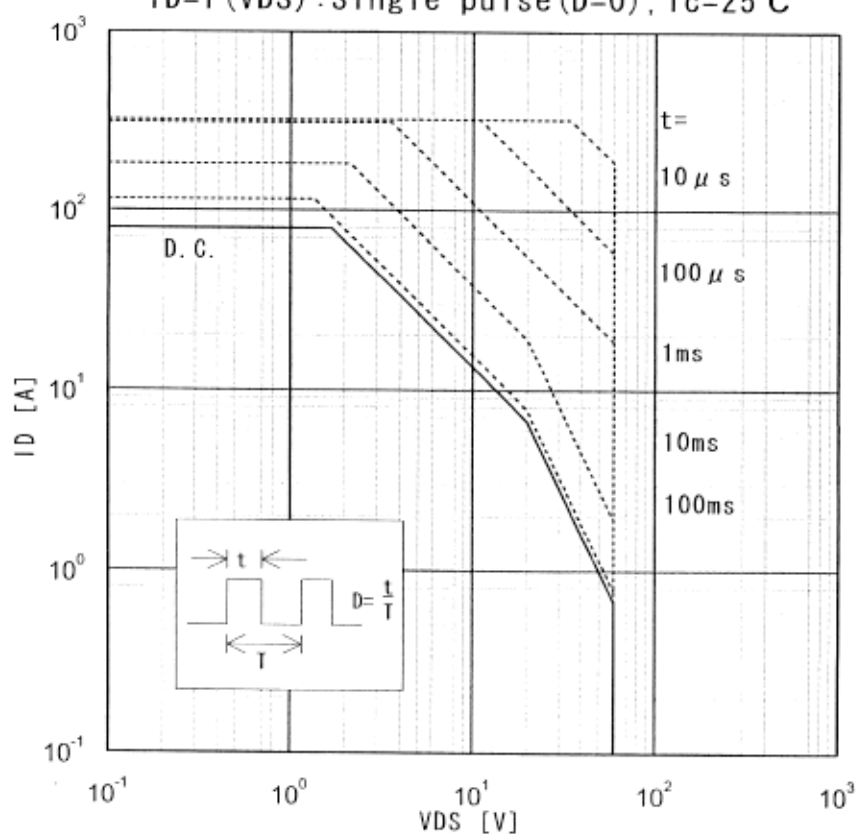
DIMENSIONS ARE IN MILLIMETERS.

Power Dissipation
 $PD=f(T_c)$

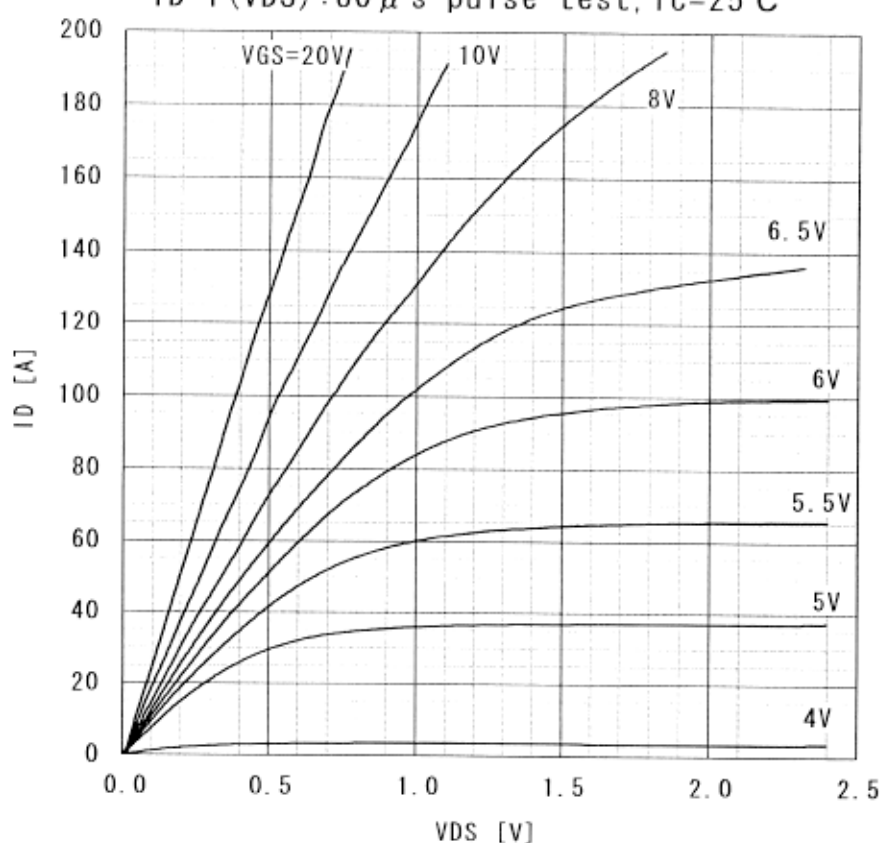


Safe operating area

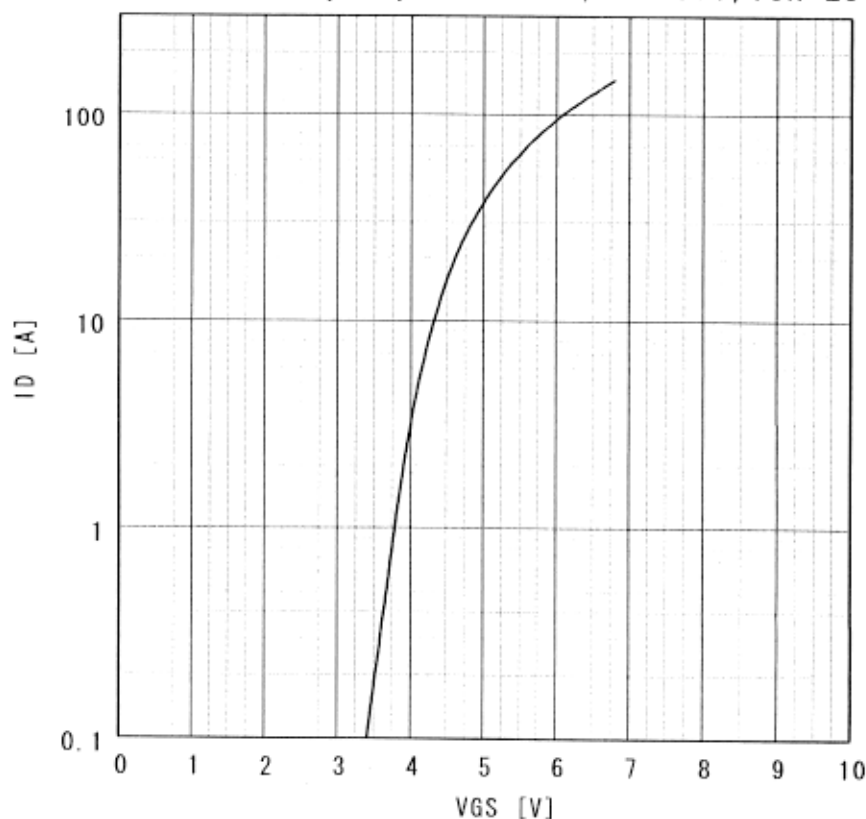
$ID=f(V_{DS})$: Single pulse ($D=0$), $T_c=25^\circ\text{C}$



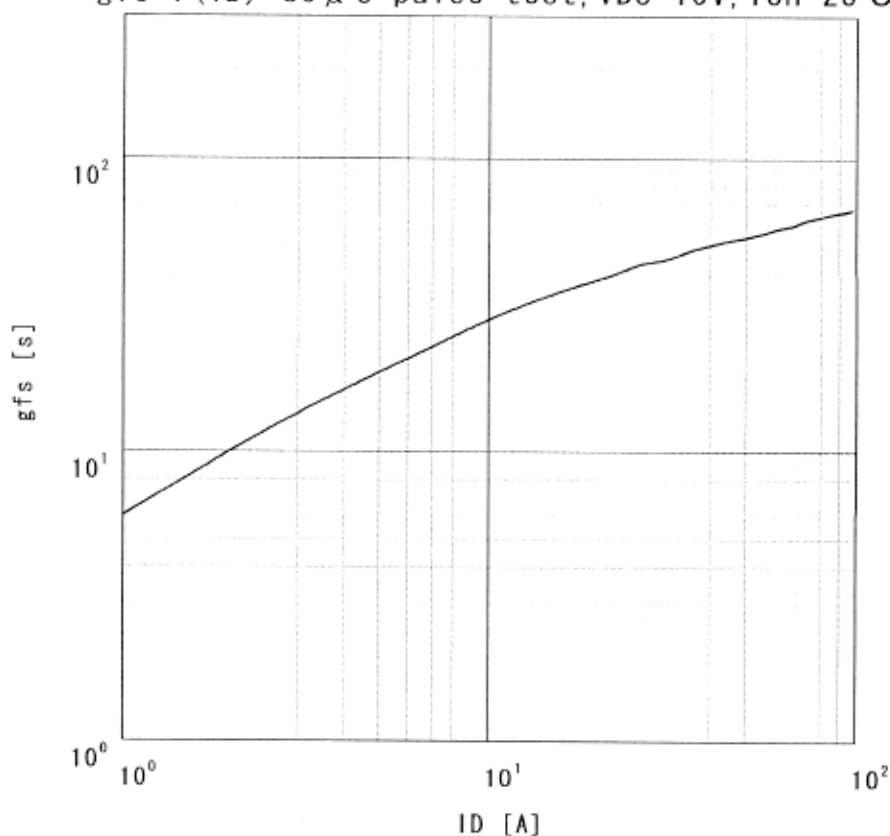
Typical output characteristics
 $I_D = f(V_{DS}) : 80 \mu s \text{ pulse test, } T_c = 25^\circ C$



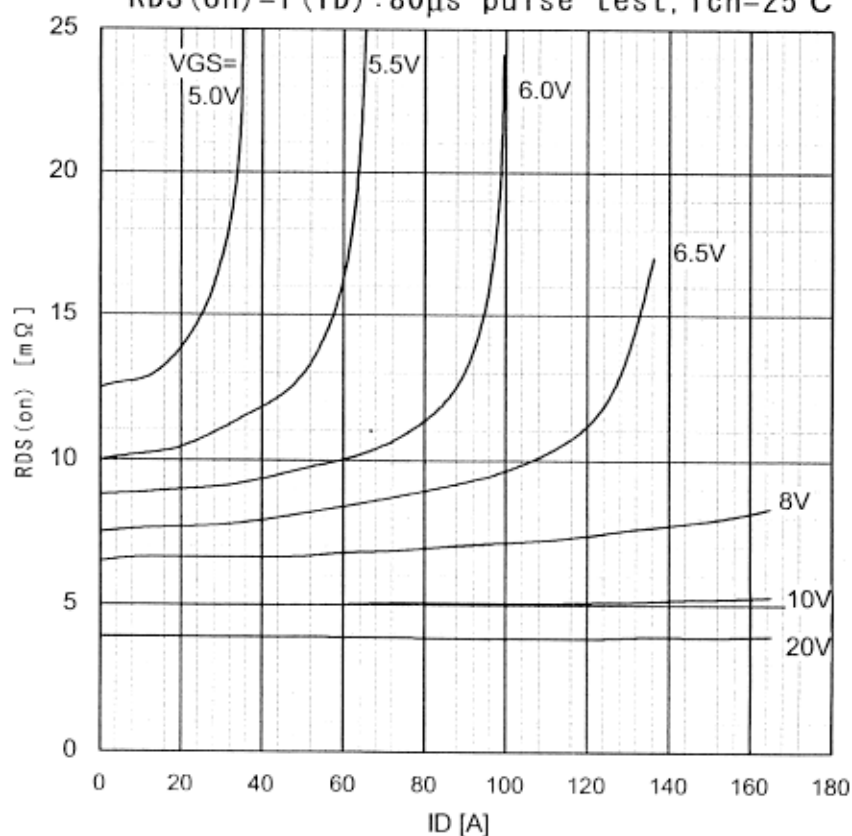
Typical transfer characteristics
 $I_D = f(V_{GS}) : 80 \mu s \text{ pulse test, } V_{DS} = 10V, T_{ch} = 25^\circ C$



Typical forward transconductance
 $g_{fs}=f(I_D)$: 80 μ s pulse test, $V_{DS}=10V$, $T_{ch}=25^\circ C$

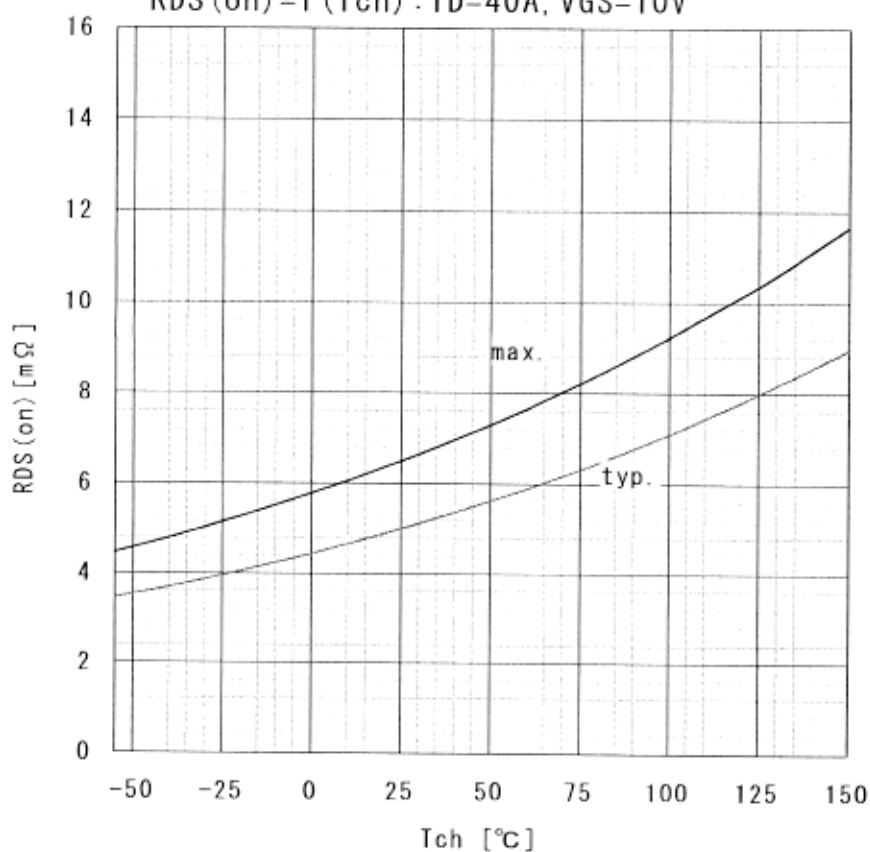


Typical Drain-Source on-State Resistance
 $R_{DS(on)}=f(I_D)$: 80 μ s pulse test, $T_{ch}=25^\circ C$



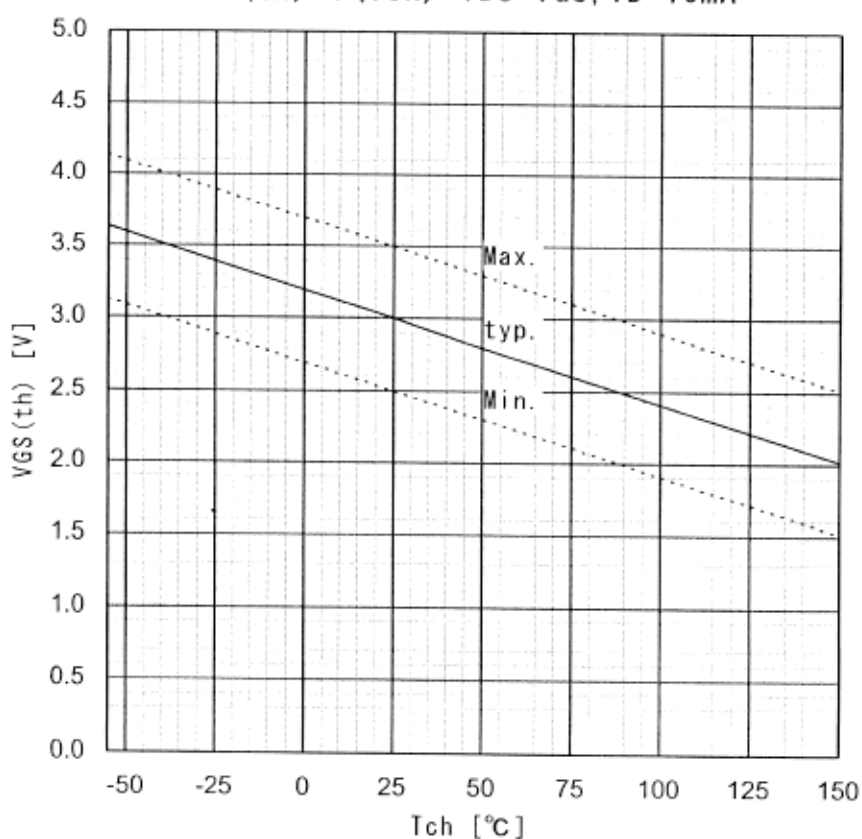
Drain-source on-state resistance

$R_{DS(on)} = f(T_{ch}) : I_D = 40A, V_{GS} = 10V$

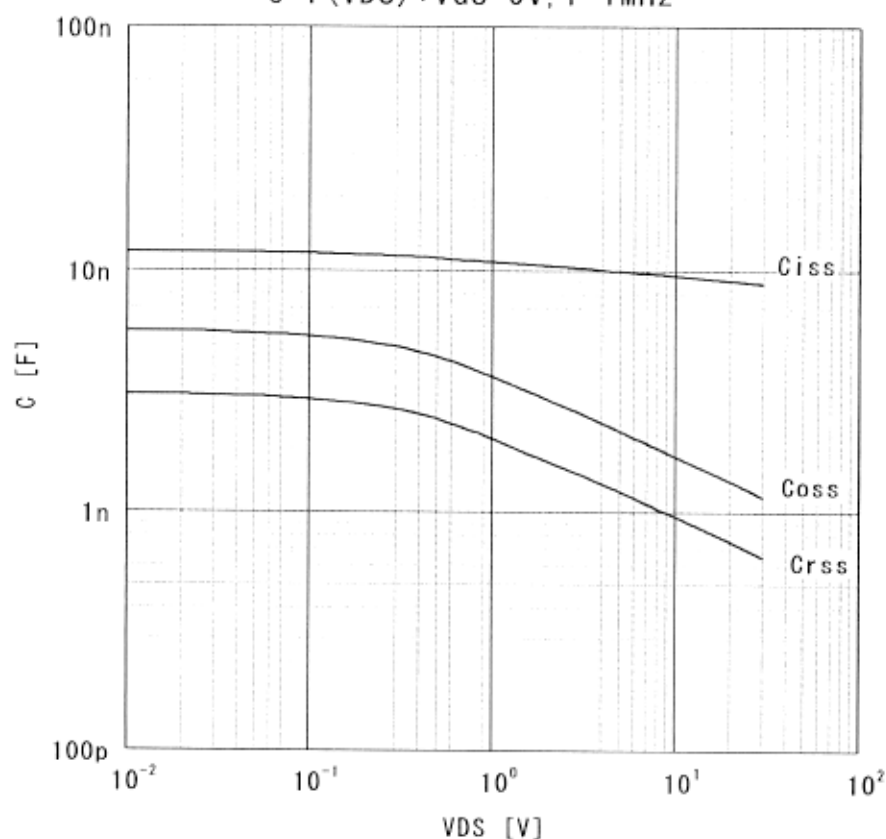


Gate Threshold Voltage vs. Tch

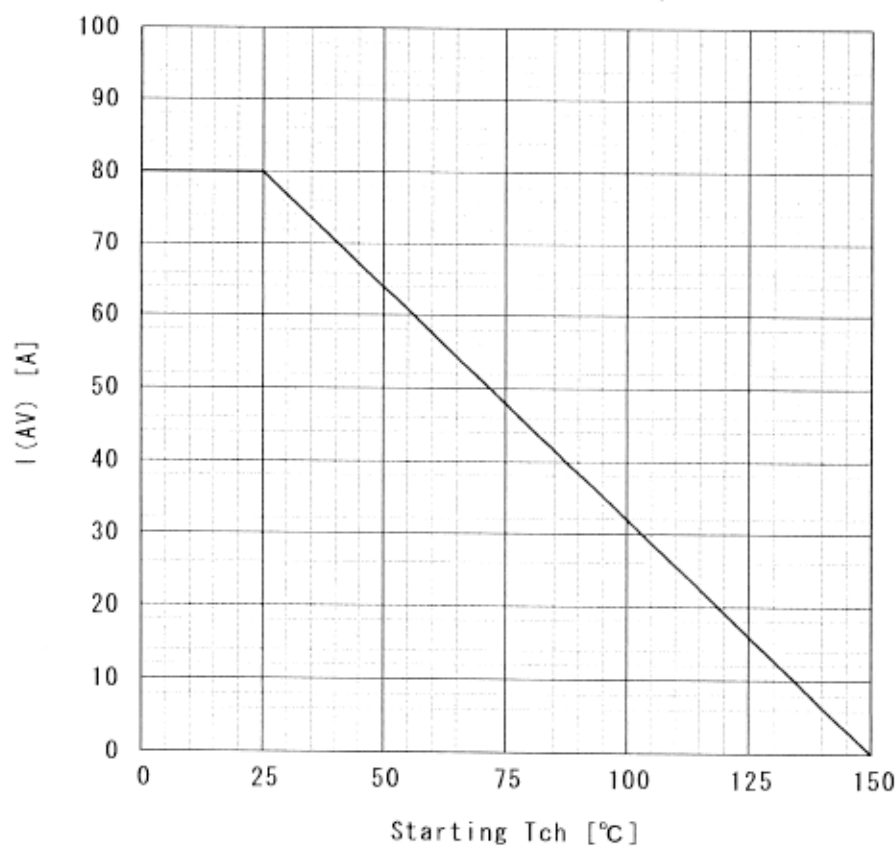
$V_{GS(th)} = f(T_{ch}) : V_{DS} = V_{GS}, I_D = 10mA$



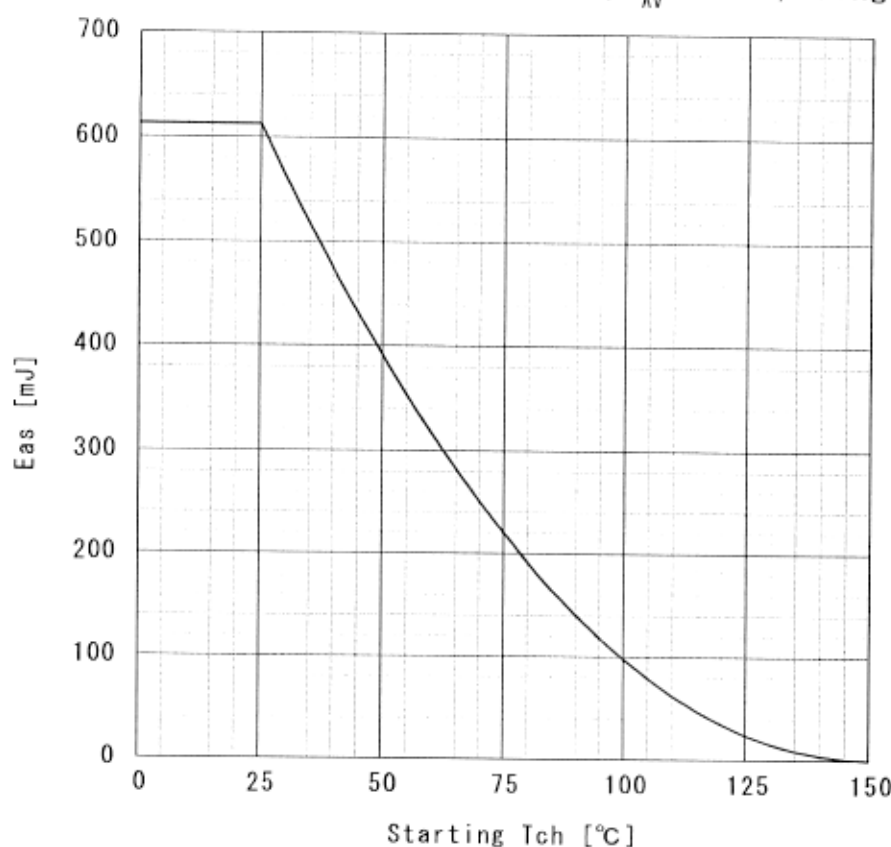
Typical capacitances
 $C=f(V_{DS}) : V_{GS}=0V, f=1MHz$



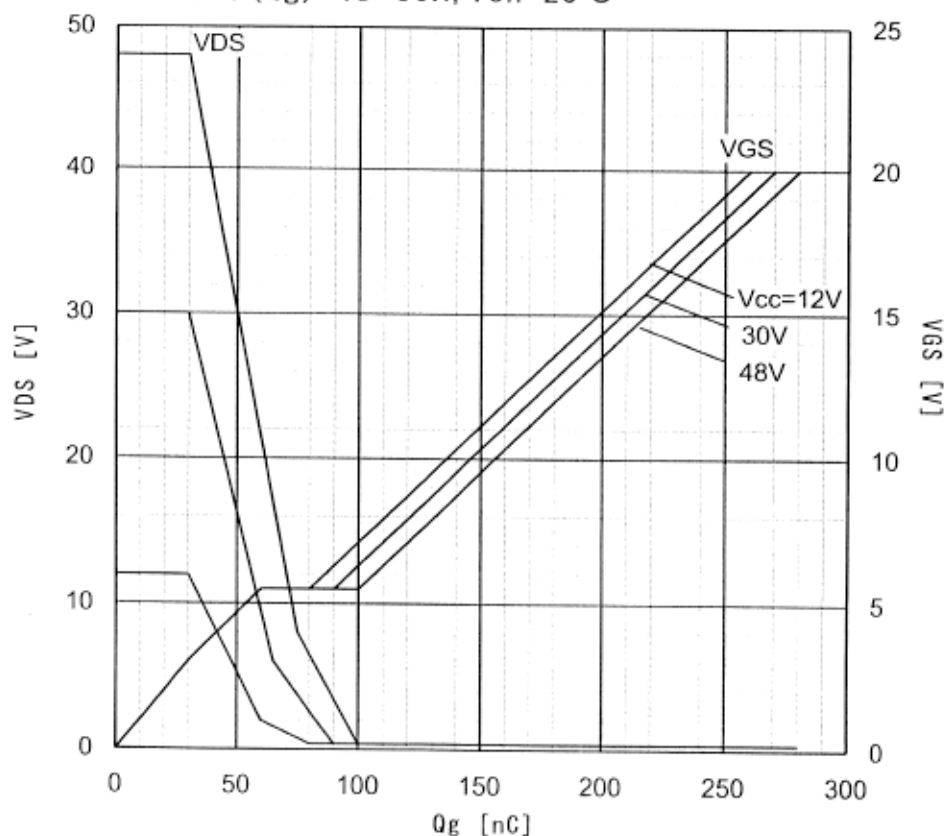
Maximum Avalanche Current vs. starting T_{ch}
 $I(AV)=f(\text{starting } T_{ch})$, single pulse



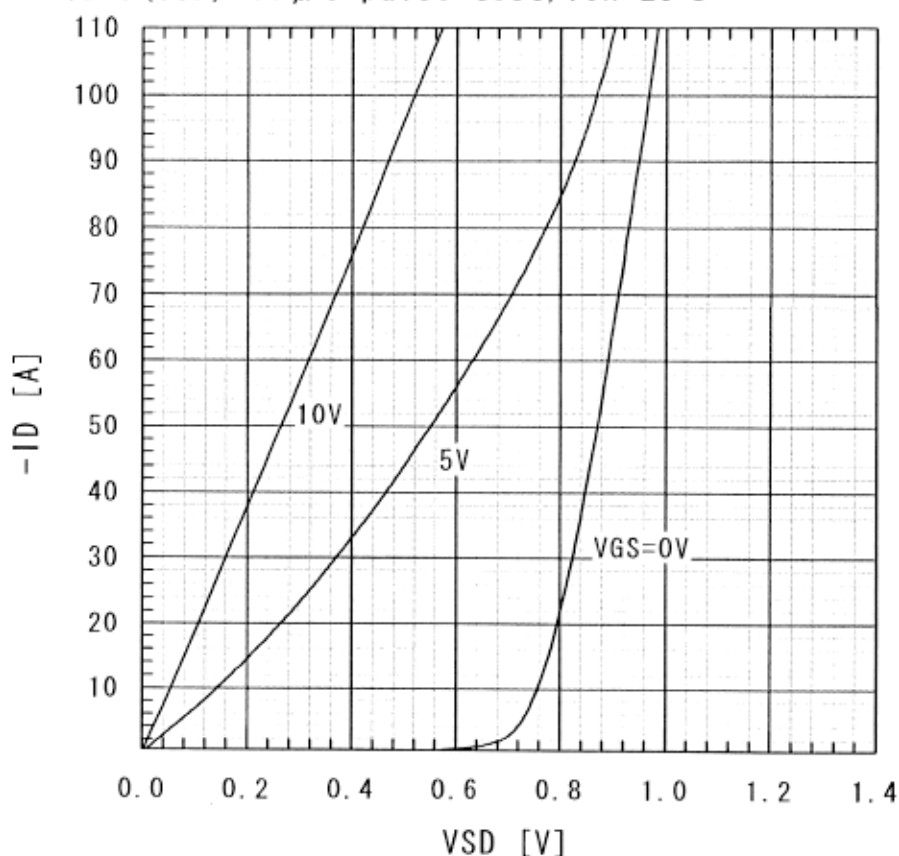
Maximum Avalanche energy vs. starting Tch
 $E_{as}=f(\text{starting Tch}) : V_{cc}=24V, I_{AV} \leq 80A$, single pulse



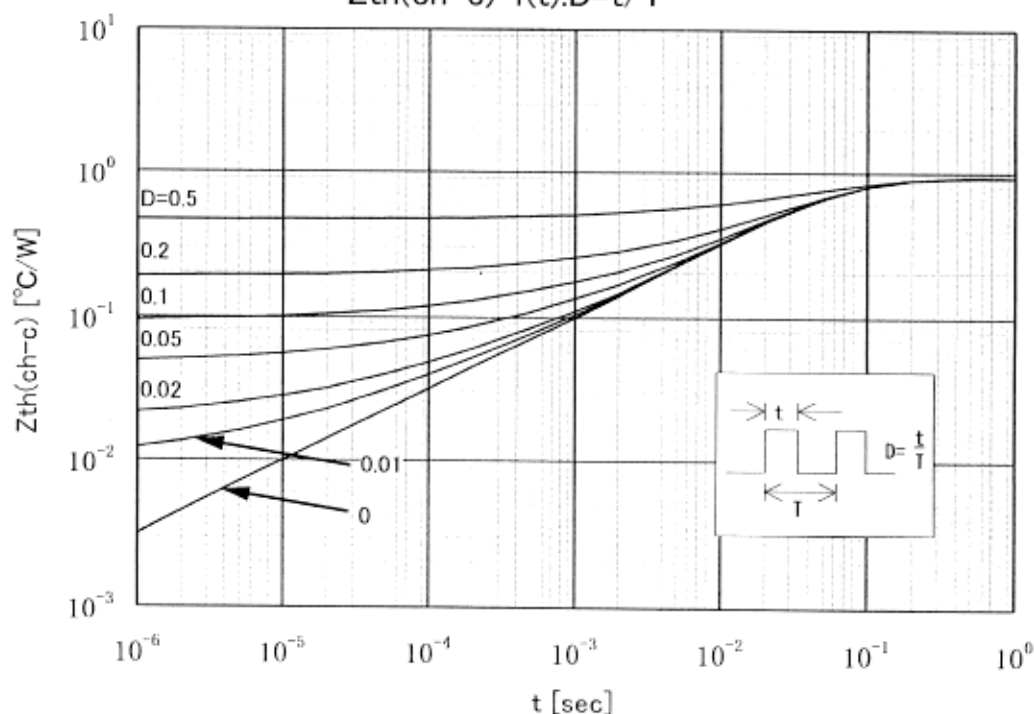
Typical Gate Charge Characteristics
 $V_{GS}=f(Q_g) : I_D=80A, Tch=25^\circ C$



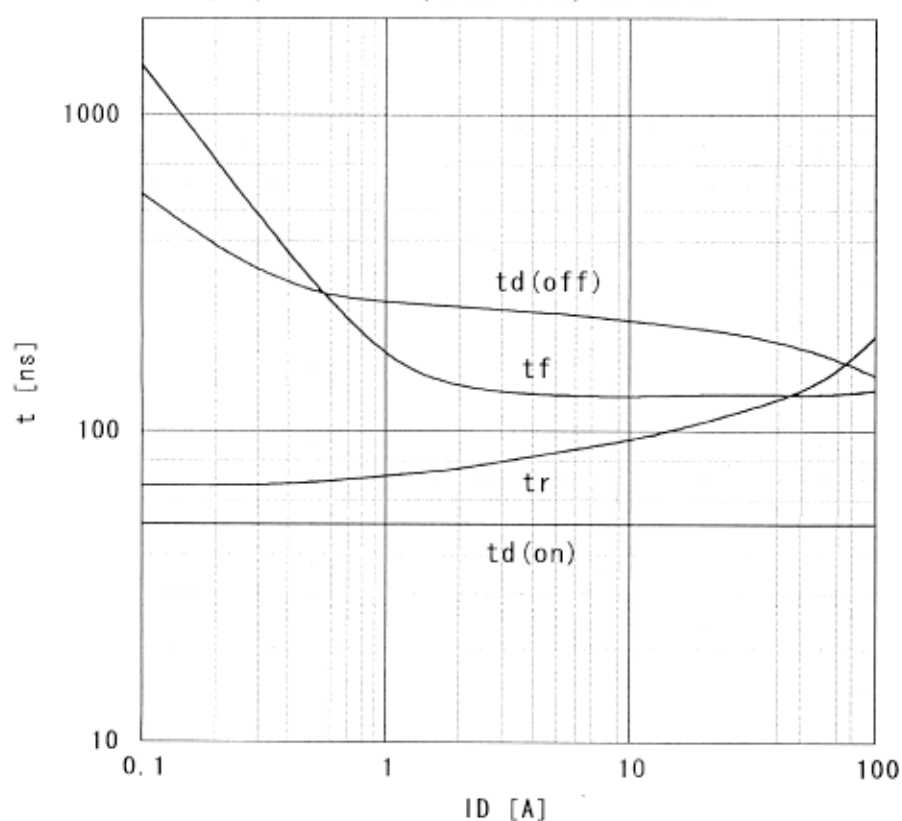
Typical Forward Characteristics of Reverse Diode
 $-I_D = f(V_{SD}) : 80 \mu s$ pulse test, $T_{ch} = 25^\circ C$



Transient Thermal Impedance
 $Z_{th(ch-c)} = f(t) : D = t/T$



Typical Switching Characteristics vs. I_D
 $t = f(I_D) : V_{CC} = 30V, V_{GS} = 10V, R_G = 10\Omega$



Drain-Source Breakdown Voltage vs. V_{GS}
 $BV_{DSX} = f(V_{GS}) : T_{ch} = 25^\circ C$

